SPECIFICATION AMENDMENTS

Please amend the title of the application to read as follows:

WAVELENGTH MULTIPLEXER/DEMULTIPLEXER

Please replace paragraph [0035] with the following:

[0035] As above, the thickness of the dielectric multilayer film 5 is $30\mu m$ and that of the substrate 51 is $5\mu m$, so the dielectric multilayer film 5 and the substrate 51 are inserted into the groove 4. Therefore, the half of total thickness of $30\mu m + 5\mu m = 35\mu m$ (17.5 μm) is the distance from the multilayer surface 5s to the center of the <u>dielectric multilayer filter including the substrate 51</u> [[groove 4]]. Also, since the distance X from the multilayer film surface 5s to the intersection point C1 of the optical waveguides is $6\mu m$, the distance from the intersection point C1 of the optical waveguides to the center of the <u>dielectric multiplayer filter including the substrate 51</u> [[groove 4]] is $17.5\mu m - 6\mu m = 11.5\mu m$.

Please replace paragraph [0036] with the following:

[0036] That is, the center of the <u>dielectric multiplayer filter including the substrate 51</u> [[groove 4]] is positioned at a distance of 11.5 μ m apart from the intersection point C1 of the optical waveguides, and the groove 4 is arranged to be perpendicular to the perpendicular bisector of the optical waveguides 2 and 3 and with a wider width than the total thickness of the dielectric multilayer film 5 by 2μ m to 3μ m.

Please replace paragraph [0053] with the following:

[0053] For the demultiplexing characteristic obtained by the reflection from the optical waveguide 2 to the optical waveguide 3, a flat and low-loss characteristic is obtained in the longer wavelength than 1550 nm [[µm]], shows as shown in FIG. 4, and the problem in the prior art, the increased loss in the long wavelength band is solved.

Please replace paragraph [0059] with the following:

[0059] In the experiment, the set position of the dielectric multilayer film 5 is changed from the position where the intersection point C1 is set at the multilayer film surface 5s (distance "X = 0" in FIG. 2A) to the position where the intersection point C1 is set at the boundary of the dielectric multilayer film 5 and the substrate 51 (distance "X = d" in FIG. $\underline{2C}$ [[2B]]). The dielectric multilayer filter 5 is a short wavelength pass filter having an alternating multilayer of SiO₂ and Ta₂O₅ with a thickness of 30 μ m stacked on a polyimide thin-film substrate (substrate 51) with a thickness of 5 μ m, and its edge wavelength of the stop (reflection) band is set around 1530nm.